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Outline

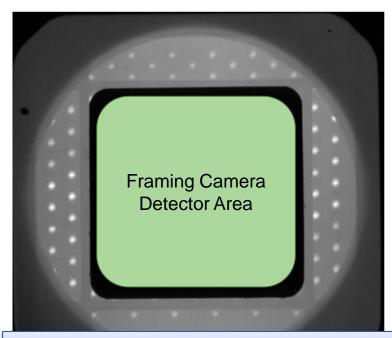
- Applications of time-integrated X-ray imaging at NIF
- Charge-Injection Device (CID) imaging sensor characteristics
- CID Camera X-ray Imager (CCXI) system implementation at NIF
 - Mechanical Design
 - Electrical Design
- CCXI calibration
- CCXI preliminary performance data and radiation hardness at NIF
- Conclusions and Future Work

Collaborators

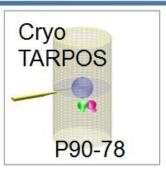
- National Security Technologies, LLC (NSTec, Livermore Operations)
 - M. J. Haugh, J. J. Lee, E. D. Romano



There Are Many Applications of Time-integrated X-ray Imaging at NIF



206 um

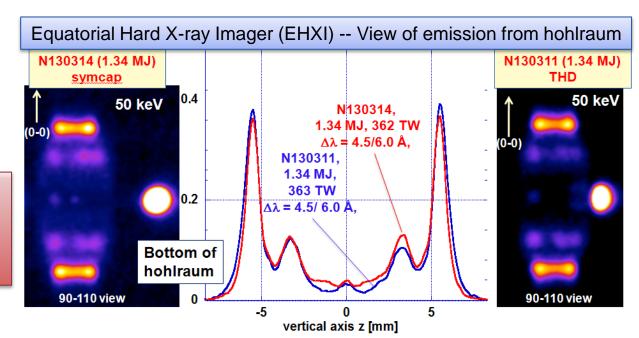


Time-integrated shape of ICF capsule implosion

P0	54.54	+/-	0.485	um
P2	3.375	+/-	0.126	um
P4	2.219	+/-	0.148	um
P2/P0	6.188	+/-	0.23	%
P4/P0	4.069	+/-	0.271	%

Image plate around periphery of primary diagnostic (framing camera or streak camera) for time-integrated imaging and verification of diagnostic positioner alignment.

Due to the harsh neutron environment (~10⁹ n/cm²), most time-integrated X-ray imaging at NIF is currently recorded on image plate or film.





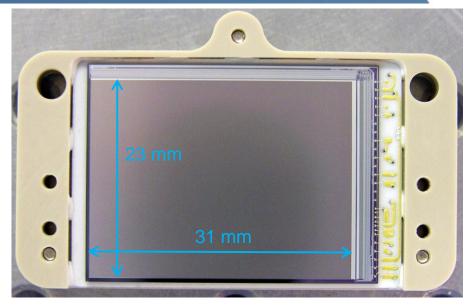
Advantages of Electronic Readout vs. Image Plate or Film

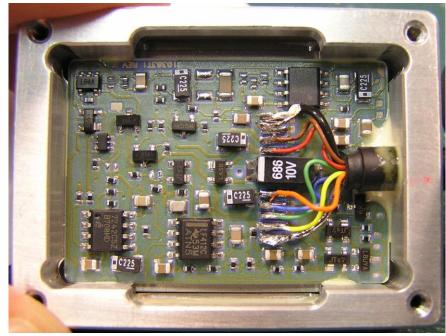
- Rad hard Charge-Injection Device (CID) cameras can replace image plates in certain applications at NIF, leveraging significant advantages of electronic readout:
 - Data available within seconds after the shot instead of hours to days later for image plate or film
 - Much more efficient operation No access to Target Chamber or diagnostics is required to retrieve the data
 - Enhanced safety Technicians avoid rad dose they would otherwise receive going in to retrieve media
- One disadvantage of electronic sensors:
 - Saturation limit of CIDs ~ 10x less than image plate; IP and film can obtain useable data on higher yield shots



CID4150 Imager from Thermo Scientific, CIDTEC Cameras

- Sensor selected based on successful use on ICF experiments at OMEGA (LLE)
- Highly compact device (31 x 23 x 5 mm) originally developed for dental X-ray imaging
- 800 x 600 array, 38.5 μm (square) pixels;
 large full well capacity > 10⁶ e⁻
- Operated at room temperature (no thermoelectric cooling), in vacuum or in air
 - Integration time limited to < ~5 sec. due to high dark current and limitations of readout electronics. (Integration time used at NIF = 100 ms)
- Uncoated sensor => Direct X-ray detection
 - X-ray sensitivity range: 1 15 keV
 - Phosphor coatings are available to extend Xray sensitivity up to ~ 100 keV. Phosphor thickness can be tailored to energy range of interest.







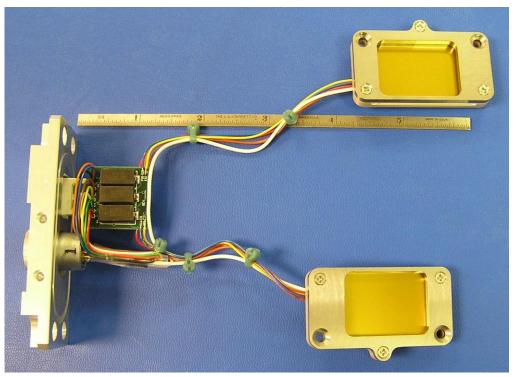
CID4150 Imager Characteristics (continued)

- Rad Hard Lifetime Dosage = 300 krad(Si) at 60 90 keV
 - This is ~ 20x higher than typical CCD cameras [10 20 krad(Si), n-channel]
 - CIDs fab'ed using high-resistivity p-channel process. Other CID cameras available with lifetime dosage > 3 Mrad(Si) (60Co source)
 - Analog video output, 1.0 Vpp, using discrete analog components (more rad hard than high-density digital circuitry)
- Readout is progressive @ 500 kHz => ~ 1 sec to read out 800 x 600 image
 - Nondestructive readout capability of CIDs not implemented for this camera
- Analog output transmitted via coax. cable to 16-bit digitizer
- Dynamic Range (estimated by vendor) > 1000:1
- Limiting Resolution: 10 LP/mm

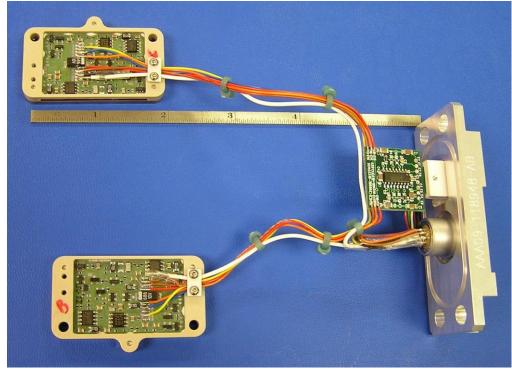


CCXI Assembly for Fielding on DIM*-based Diagnostics at NIF

CCXI = CID Camera X-ray Imager



- 2 CID camera modules
- 3 mm thick tungsten frame shields edges of sensors, protects on-chip logic
- 25 µm Kapton® film, protective cover over face of sensor
- Small interface circuit board: DC power filters (EMI protection) and differential line receivers for CLOCK and TRIG signals

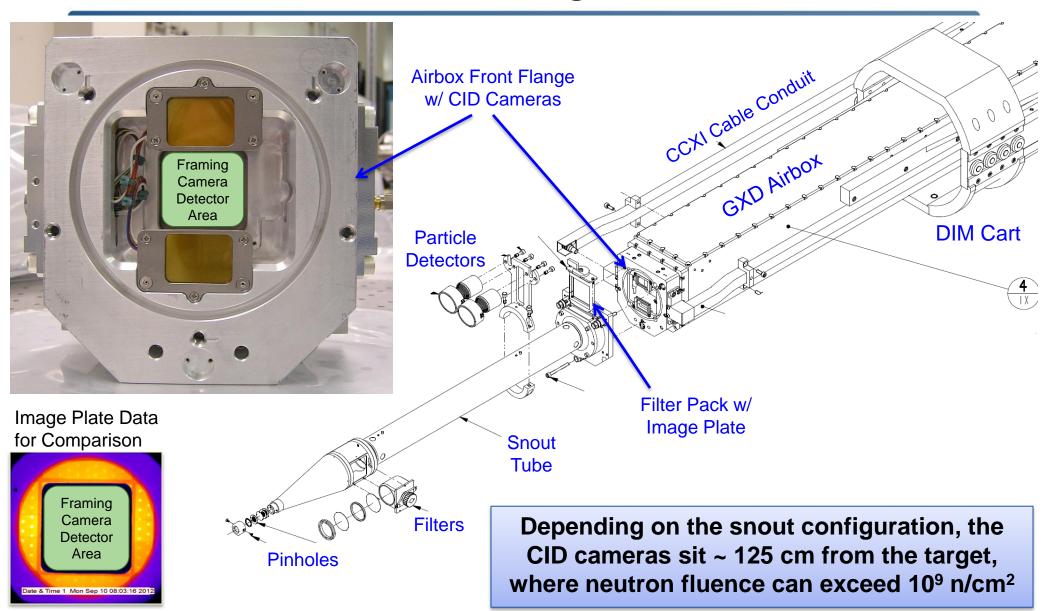


- Video signal (image) output via micro coax.
- All other signals via Tefzel-jacketed hook-up wire.
- All materials meet stringent NIF requirements for cleanliness and low outgassing

* DIM = Diagnostic Instrument Manipulator



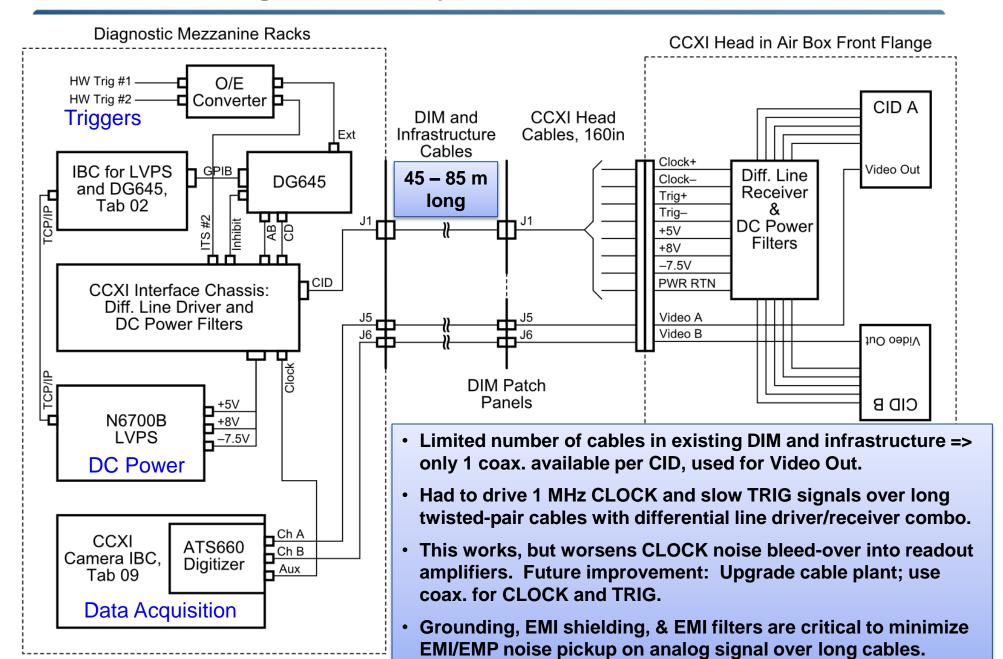
CCXI Mounted on DIM-based Diagnostic



(Drawing excerpt from AAA10-106125-AA, GXD DLP Assy., 4x Mag.)

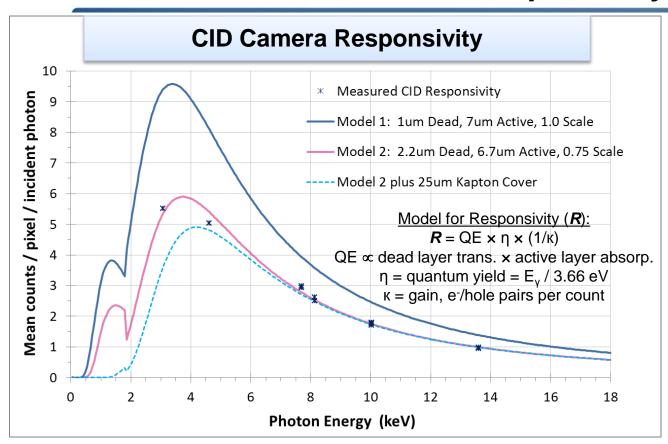


Electrical Design – CCXI System Schematic





CID Camera Calibration – Responsivity



Significant challenges to calibrate these CID cameras. Short exposure + limited X-ray flux from cal. sources + low responsivity of CIDs =>

- Photon statistics in individual images overwhelmed by other sources of noise (readout and pattern noise)
- Large number of images (~50) required to improve signal-to-noise
- Background images must be acquired within seconds of X-ray images

(See paper for additional details of how these challenges were overcome.)

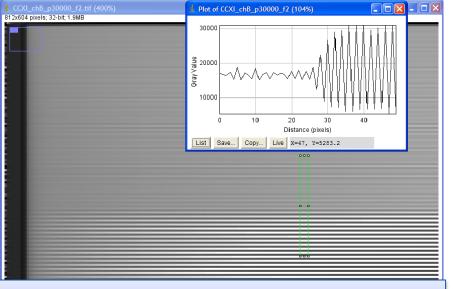
- Responsivity measured at NSTec using Manson (3 7.7 keV) and HEX (8 14 keV) X-ray sources.*
- Model 1 uses initial estimates 1 um dead layer, 7 um active layer, $\kappa = 56 \, e^{-1}$ hole pairs per count.
- Model 2 adjusted for better fit to data 2.2um dead layer, 6.7um active. 0.75 scale factor accounts for errors in initial estimates of gain, pixel active area, and charge collection efficiency.
- 25 µm Kapton® cover further reduces low energy response.



CID Camera Calibration – Linearity and Resolution

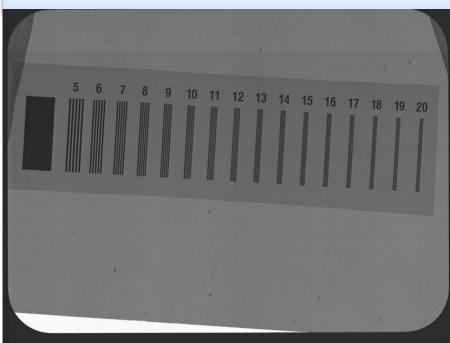
Linearity

- Visible light used instead of X-rays to produce enough counts to span full linear range.
- Discovered nonphysical saturation behavior
 - For flat-field illumination: Output linear up to ~ 16,000 counts/pixel (~ 1 V), then output starts to "oscillate", every other row high then low, producing bands (image below).
 - For small bright spot: Output linear up to ~ 20,000 counts/pixel (~ 1.2 V) if illumination confined to small region on sensor (such as pinhole image of ICF target).
- This appears to be a limitation of the integrated readout electronics (rated 1.0 Vpp), not the CID chip itself.



CCXI image showing onset of saturation oscillation with alternating rows of high and low counts

Resolution



- Illumination from Manson source, Ti anode, no filter (~ 4.6 keV X-rays)
- Average of 50 images, 1 sec. exposures, background-subtracted
- Dark outer edges are shadow of tungsten frame

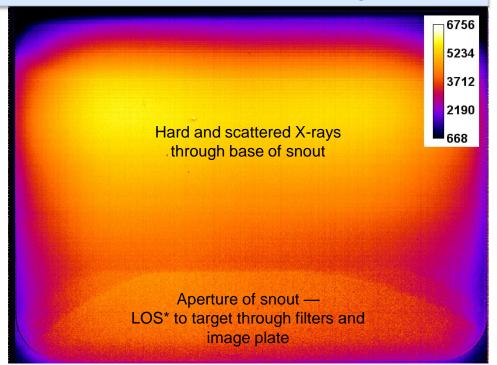
Limiting Resolution:

 $MTF^* = 50\%$ at $\approx 10 LP/mm$

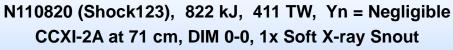


CCXI Images from Shots on NIF – Noise and Dynamic Range

N110807 (Symcap), 1.3 MJ, 417 TW, Yn (DD) = 3.7E+11CCXI-2A at 125 cm, DIM 0-0, 12x Mag Snout



- For these preliminary tests, no imaging line of sight for CCXI, just diffuse illumination through snout and filters
- Typical Noise (Std. Dev.) ≈ 200 400 cts (100 x 100 pixel center region of preshot background image)
- Saturation limit for broad illumination ≈ 16,000 cts => Dynamic range ≈ 40:1 – 80:1





- Saturation limit for small bright spot ≈ 20,000 cts => Dynamic range ≈ 50:1 – 100:1
- Noise could be reduced with cable upgrade and EMI shielding improvements.
- High dark current also eats away dynamic range by raising bias level of noise floor. Cooling the sensor would help, but would also add complexity.



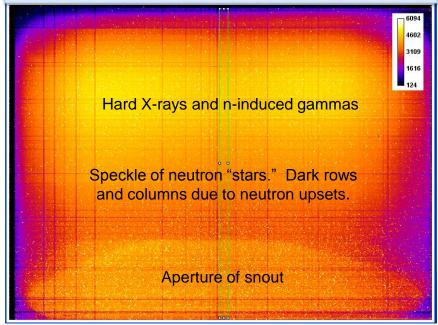
CCXI Saturation Limits With High Neutron Fluence

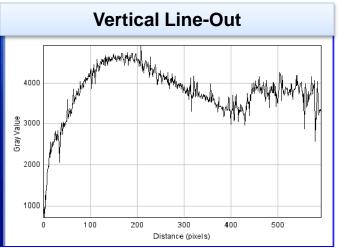
- CCXI obtained usable data (see image to the right) w/ n-fluence 2.4E+7 n/cm² (Yn = 4.27E+12) and 4.3E+7 n/cm² (Yn = 8.5E+12)
- CCXI saturated on shots with n-fluence > 8.8E+8 n/cm² (Yn > 1.7E+14).
- Exact neutron saturation limit of CCXI not measured (no shots with Yn ~ 10¹³ range), but results above are consistent with results at OMEGA** and calculations* of CID saturation vs. image plate (table below).

Estimated Saturation Limits* for CIDs vs. Image Plate				
Detector:	BAS-SR Image Plate	CID4150 for CCXI		
Pixel size	25um	38.5um		
Material	BaFBr(Eu)	Si		
Protection layer	PET ~7um	SiO2 ~1um		
Sensitive layer	39 mg/cm2	1.63 mg/cm2		
Energy absorption @ 10keV	97.5%	5.2%		
Saturation limit	1.265E+5 PSL/mm2	1E+6 electron/pix		
Signal saturation (absorbed)	63 erg/cm2	0.40 erg/cm2		
14 MeV Neutron sensitivity	~1.3 keV/inc. n	130 eV/ inc. n		
n-fluence equiv. to saturation	3E+10 n/cm2	1.9E+9 n/cm2		
Practical n-fluence limit	3E+9 n/cm2	3E+8 n/cm2**		
Practical Yn limit at 125 cm	5.9E+14	5.9E+13		

^{*} Calculations by N. Izumi, LLNL, 8/15/2011

CCXI-2B Image from Shot N110804 (THD) 14 MeV n-Fluence = 2.4E+7 n/cm²

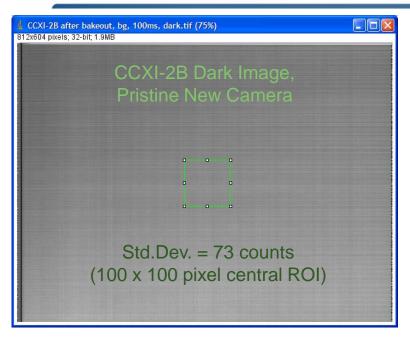




^{**} Marshall, F. J., DeHaas, T., and Glebov, V. Y., Rev. Sci. Instrum. 81, 10E503 (2010)



CCXI Survives High Fluence of X-rays and Neutrons with Minimal Damage



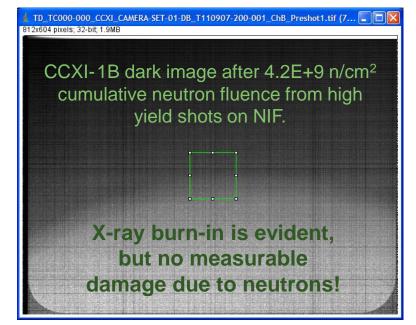
CCXI-2B dark image w/ burn-in after multiple low-n-yield shots on NIF (burn-in from X-rays only)

Std.Dev. = 124 counts (1.7x increase)

Mean increased by 558 counts due to higher dark current

- After multiple low-neutron-yield shots at NIF, CCXI-2 had some X-ray burn-in damage as shown to the left. X-ray burn-in can be minimized with appropriate filtering.
- Series of high-neutron-yield shots (see table) with CCXI-1 at 125 cm from target (cumulative 14 MeV neutron fluence ~ 4.2 × 10⁹ n/cm²) Images were highly saturated and cameras experienced upsets, but subsequent dry run images showed no measurable damage due to neutrons.

Shot ID	DT n Yield, 14 MeV	DT Neutron Fluence* at CCXI (n/cm²)
N110608	1.93×10^{14}	9.8 × 10 ⁸
N110826	1.72×10^{14}	8.8×10^8
N110904	4.50×10^{14}	2.3×10^9



* Includes primary DT neutron fluence only. Total fluence including scattered neutrons was higher than this.



Conclusions and Future Work

- CID camera X-ray Imager has been successfully designed, built, calibrated, and fielded at NIF on DIM-based diagnostics (GXD and hGXI) in DIM 0-0 and in DIM 90-78.
 - CCXI was not commissioned in DIM 90-315 due to shorts in infrastructure cable.
- CCXI calibration Responsivity measured for X-rays from 3 14 keV. Linearity and Resolution also characterized. CIDs are suitable for various imaging applications at NIF.
- CCXI performance and radiation hardness have been evaluated at NIF in a harsh neutron environment.
 - CCXI can acquire usable images up to $\sim 10^8$ n/cm² (shot yield of $\sim 5 \times 10^{13}$ with CID at 125 cm from target).
 - CCXI images saturate at higher fluence, but CIDs survive with no measurable damage due to neutrons. (Tested up to 4.2 × 10⁹ n/cm² cumulative DT neutron fluence.)
- Future Improvements and Applications:
 - Upgrade cable plant to transmit CLOCK and TRIG signals via coax. instead of differential line pair, thereby reducing noise coupling into readout. Improve EMI shielding.
 - Fine-tune delay of CLOCK signal to get optimal analog-to-digital samples where noise in readout signal is lowest.
 - Adapt CID cameras for other imaging applications at NIF such as EHXI (Equatorial Hard X-ray Imager).

